

Notice of References Cited	Application/Control No. 10/047,781		Applicant(s)/Patent Under Reexamination DOR ET AL.	
	Examiner Jason Proctor		Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,763,130 B1	07-2004	Somekh et al.	382/145
*	B	US-6,496,596 B1	12-2002	Zika et al.	382/149
*	C	US-5,761,064 A	06-1998	La et al.	700/110
*	D	US-6,240,329 B1	05-2001	Sun, Chin-Yang	700/110
*	E	US-6,408,219 B2	06-2002	Lamey et al.	700/110
*	F	US-6,185,511 B1	02-2001	Steffan et al.	702/81
*	G	US-6,542,830 B1	04-2003	Mizuno et al.	702/35
*	H	US-5,963,881 A	10-1999	Kahn et al.	702/35
*	I	US-6,456,899 B1	09-2002	Gleason et al.	700/212
*	J	US-6,366,824 B1	04-2002	Nair et al.	700/115
*	K	US-6,556,959 B1	04-2003	Miller et al.	703/2
*	L	US-6,314,379 B1	11-2001	Hu et al.	702/81
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frank Poag, Douglas Paradis, Mahesh Reddy, and Jon Button; "Implementing on-line ADC and an automated yield information management system"; July 2000; www.micromagazine.com; pages 1-12
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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